



03 eo
Fischer
(K) 54 084

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re: US Patent Application 09/818,036
Filed March 26, 2001
Title Method and apparatus for the nondestructive measurement of the
thickness of thin layers
Applicant Fischer
Attorney Docket (K) 54 084

Box Missing Parts
Commissioner for Patents
Washington, DC 20231

~~TRADE~~ Further Preliminary Amendment

Dear Sir or Madam:

This is in response to the Notice to File Corrected Application Papers mailed May
31, 2001 (copy enclosed).

Please amend the above-identified application as follows:

In the Specification:

Enclosed, please find a substitute specification conforming the application text to
US style and practice with proper margins. Also enclosed is a marked-up version
showing changes made in this amendment.

In the Claims:

✓
Cancel claims 1 to 20 and insert the attached new claims 21 to 43.

In the Abstract of the Disclosure:

Attached hereto, please find a new Abstract of the Disclosure for use with this
application.

09/13/2001 EABURAK1 00000030 09818036

02 FC:215

55.00 0P